



Substitute for form 1449A/PTO				<i>Complete if Known</i>	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	10/731,089
Sheet	1	of	1	Filing Date	December 10, 2003
				First Named Inventor	Shinya SASAGAWA et al.
				Art Unit	1765
				Examiner Name	Not Assigned Yet
				Attorney Docket Number	740756-2676

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)		
MA	1	US-6,596,571 B2		07/22/2003 Arao et al.	
MA	2	US-6,646,287 B1		11/11/2003 Ono et al.	
MA	3	US-6,706,544 B2		03/16/2004 Yamazaki et al.	
MA	4	US-6,872,604 B2		03/29/2005 Yamazaki et al.	
MA	5	US-6,933,184 B2		08/23/2005 Arao et al.	
MA	6	US-2001/0041392 A1		11/15/2001 Suzawa et al.	
MA	7	US-2001/0048408 A1		12/06/2001 Koyama et al.	
MA	8	US-2002/0102776 A1		08/01/2002 Yamazaki et al.	
MA	9	US-2002/0163049 A1		11/07/2002 Yamazaki et al.	
MA	10	US-2003/0020118 A1		01/30/2003 Kajiwara et al.	
MA	11	US-2003/0062524 A1		04/03/2003 Kimura	
MA	12	US-2003/0100151 A1		05/29/2003 Okamoto	
MA	13	US-2004/0140472 A1		07/22/2004 Fujimoto et al.	
MA	14	US-2004/0171242 A1		09/02/2004 Monoe et al.	
MA	15	US-2004/0209409 A1		10/21/2004 Monoe et al.	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			²
MA	16	Y. MISHIMA et al.; "Improved Lifetime of Poly-Si TFTs With a Self-Aligned Gate-Overlapped LDD Structure"; IEEE TRANSACTIONS ON ELECTRON DEVICES; 06/01/2002; Vol. 49; No. 6; PP. 981-985			
MA	17	K. OHGATA et al.; "A New Dopant Activation Technique for Poly-Si TFTs With a Self-Aligned Gate-Overlapped LDD Structure"; IEDM: TECHNICAL DIGEST OF INTERNATIONAL DEVICES MEETING; 12/10/2000; PP. 205-208.			

Examiner Signature	/Maki Angadi/	Date Considered	09/08/2006
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